

MEM2301

P-Channel MOSFET MEM2301M3

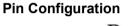
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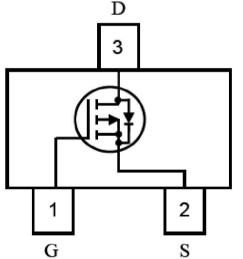
General Description

MEM2301M3G Series P-channel enhancement mode field-effect transistor ,produced with high cell density DMOS trench technology, which is especially used to minimize on-state resistance. This device particularly suits low voltage applications, and low power dissipation, and low power dissipation in a very small outline surface mount package.

Features

- -20V/-2.8A R_{DS(ON)}=93mΩ@ V_{GS}=-4.5V,I_D=-2.8A R_{DS(ON)}=113mΩ@ V_{GS}=-2.5V,I_D=-2A
- High Density Cell Design For Ultra Low On-Resistance
- Subminiature surface mount package:SOT23-3L





Typical Application

- Power management
- Load switch
- Battery protection

Absolute Maximum Ratings

Parameter		Symbol	Ratings	Unit	
Drain-Source Voltage		V _{DSS}	-20	V	
Gate-Source Voltage		V _{GSS}	±8	V	
Continuous	T _A =25℃	I.	-2.8	А	
Drain Current	T _A =70℃	Ι _D	-1.8	A	
Pulsed Drain Current ^{1,2}		I _{DM}	-10	А	
Total Power	T _A =25℃	Pd	0.7	W	
Dissipation	T _A =70℃	Fu	0.45	vv	
Operating Temperature Range		T _{Opr}	150	°C	
Storage Temperature Range		T _{stg}	-65/150	°C	



Thermal Characteristics

Parameter	Symbol	MAX.	Unit
Thermal Resistance, Junction-to-Ambient ³	RθJA	145	°C <i>I</i> W

Electrical Characteristics

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Parameter	Symbol	Test Condition	Min	Туре	Max	Unit				
Static Characteristics										
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =-250uA	-20	-23		V				
Gate Threshold Voltage	V _{GS(th)}	V_{DS} = V_{GS} , I_D =-250uA	-0.4	0.58	-1	V				
Cata Pady Laakaga	I _{GSS}	V_{DS} =0V, V_{GS} =8V		0.2	100	nA				
Gate-Body Leakage		V _{DS} =0V, V _{GS} =-8V		-0.2	-100	nA				
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-16V V _{GS} =0V		-1.5	-100	nA				
Statia Drain Source On Desistance	R _{DS(ON)1}	V _{GS} =-4.5V,I _D =-2.8A		93	110	mΩ				
Static Drain-Source On-Resistance	R _{DS(ON)2}	V _{GS} =-2.5V,I _D =-2A		113	140	mΩ				
Forward Transconductance	g fs	V_{DS} = -5 V, I_{D} = -2.8 A		6.5		S				
Source-drain (diode forward)	V	V _{GS} =0V,I _D =-1A			-1.2	V				
voltage	V_{SD}									
Dynamic Characteristics										
Input Capacitance	but Capacitance Ciss $V_{DS} = -6V$,			500						
Output Capacitance	Coss	V _{GS} = 0 V,		115		pF				
Reverse Transfer Capacitance	Crss	f = 1 MHz		60						
Switching Characteristics										
Turn-On Delay Time	td(on) $V_{DD} = -6 V$,		5	25						
Rise Time	tr	I _D =-1 A,		30	60	ns				
Turn-Off Delay Time	td(off)	V _{GEN} = -4.5 V,		25	60					
Fall-Time	tf	Rg = 6 Ω		10	60					
Total Gate Charge	Qg	V _{DS} = -6 V,	4.0 10							
Gate-Source Charge	Qgs	V _{GS} = -4.5 V,		0.8		nc				
Gate-Drain Charge	Qgd	I _D = -2.8A		0.8						

1. Pulse width limited by maximum junction temperature.

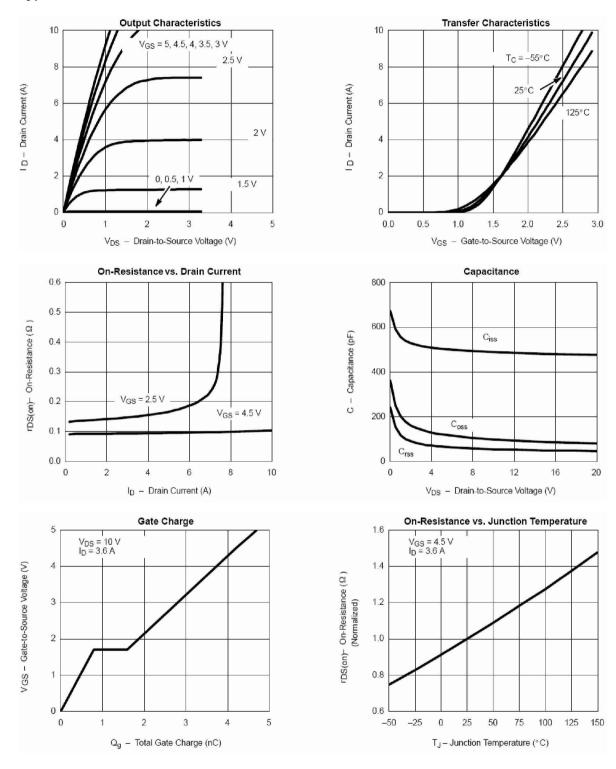
2. Pulse test: PW \leq 300 us duty cycle \leq 2%.

3、Surface Mounted on FR4 Board, t $\,\leq\,$ 5 sec.



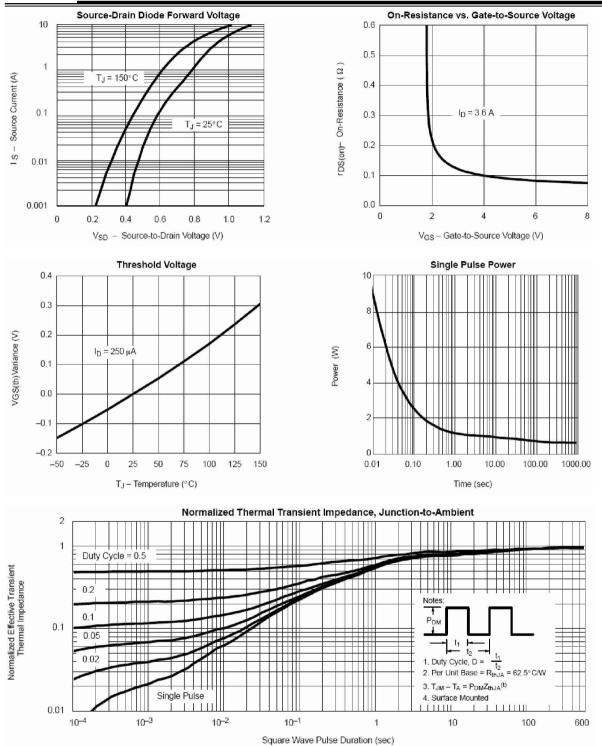
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Typical Performance Characteristics



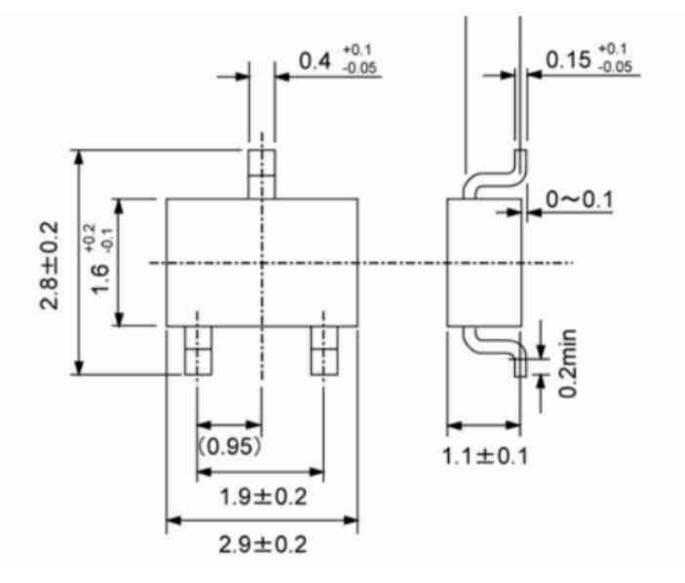


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Package Information





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